

BEST AVAILABLE COPY

SEARCHED

[illegible]

SEARCH NOTES

(INCLUDING SEARCH STRATEGY)

| | Date | Exmr. |
|---|-------------|----------|
| West ACM, IEEE Cite seer (Web) Key: debug circuit pat/m & Inventor search | 8/12/3 | TTL |
| West, ACM, IEEE Citeseer | 5/13/4 ✓ | TTL ✓ |

INTERFERENCE SEARCHED

| Class | Sub. | Date | Exmr. |
|-------|------|------|-------|
| | | | |

(RIGHT OUTSIDE)